# 2SC3979, 2SC3979A

## Silicon NPN triple diffusion planar type

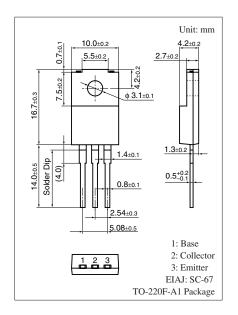
For high breakdown voltage high-speed switching

#### ■ Features

- High-speed switching
- ullet High collector-base voltage (Emitter open)  $V_{CBO}$
- Wide safe operation area
- Satisfactory linearity of forward current transfer ratio h<sub>FE</sub>
- Full-pack package which can be installed to the heat sink with one screw

#### ■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit		
Collector-base voltage	2SC3979	$V_{CBO}$	900	V	
(Emitter open)	2SC3979A		1 000		
Collector-emitter voltage	2SC3979	V <sub>CES</sub>	900	V	
(E-B short)	2SC3979A		1 000		
Collector-emitter voltage	V <sub>CEO</sub>	800	V		
Emitter-base voltage (Col	V <sub>EBO</sub>	7	V		
Base current	$I_B$	1	A		
Collector current	$I_C$	3	A		
Peak collector current	$I_{CP}$	5	A		
Collector power	P <sub>C</sub>	40	W		
dissipation	$T_a = 25^{\circ}C$		2.0		
Junction temperature	$T_{j}$	150	°C		
Storage temperature	T <sub>stg</sub>	-55 to +150	°C		

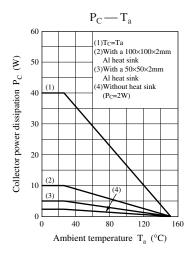


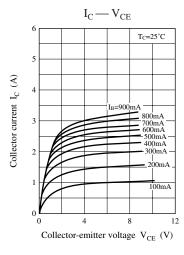
## ■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

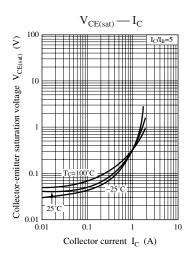
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)		V <sub>CEO</sub>	$I_C = 10 \text{ mA}, I_B = 0$	800			V
Collector-base cut-off current	2SC3979	$I_{CBO}$	$V_{CB} = 900 \text{ V}, I_E = 0$			50	μΑ
(Emitter open)	2SC3979A		$V_{CB} = 1000 \text{ V}, I_E = 0$			50	
Emitter-base cutoff current (Collector open)		$I_{EBO}$	$V_{EB} = 7 \text{ V}, I_{C} = 0$			50	μΑ
Forward current transfer ratio		h <sub>FE1</sub>	$V_{CE} = 5 \text{ V}, I_{C} = 0.1 \text{ A}$	8			_
		h <sub>FE2</sub>	$V_{CE} = 5 \text{ V}, I_{C} = 0.8 \text{ A}$	6			
Collector-emitter saturation	voltage	V <sub>CE(sat)</sub>	$I_C = 0.8 \text{ A}, I_B = 0.16 \text{ A}$			1.5	V
Base-emitter saturation volt	age	V <sub>BE(sat)</sub>	$I_C = 0.8 \text{ A}, I_B = 0.16 \text{ A}$			1.5	V
Transition frequency		$f_T$	$V_{CE} = 5 \text{ V}, I_{C} = 0.15 \text{ A}, f = 1 \text{ MHz}$		10		MHz
Turn-on time		t <sub>on</sub>	$I_C = 0.8 \text{ A}$			0.7	μs
Storage time		t <sub>stg</sub>	$I_{B1} = 0.16 \text{ A}, I_{B2} = -0.32 \text{ A}$			2.5	μs
Fall time		$t_{\rm f}$	$V_{CC} = 250 \text{ V}$			0.3	μs

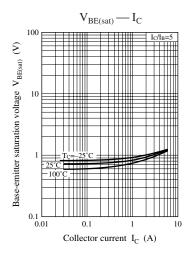
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

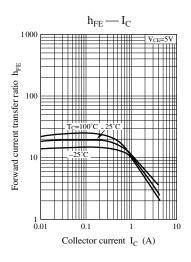
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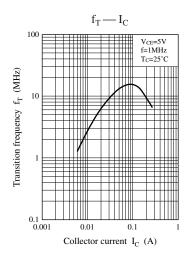


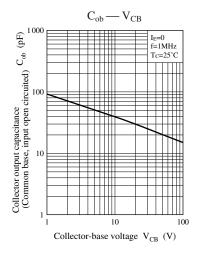


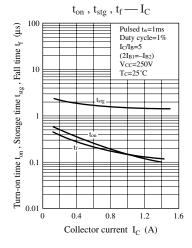


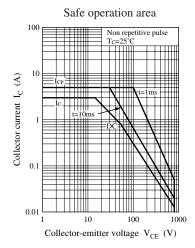








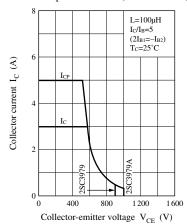




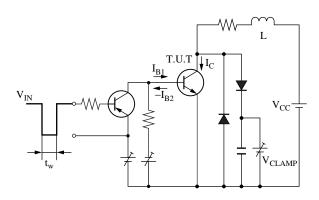
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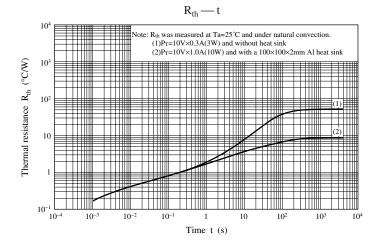
## **Panasonic**

Safe operation area (Reverse bias)



Safe operation area (Reverse bias) measurement circuit





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